

<b>FORM PTO-1449</b> U.S. Department of Commerce Patent and Trademark Office <i>NOV 09 2004</i>		<b>Docket No.</b> INTEL1120 (P15611)	<b>Serial No.:</b> 10/748,389
<b>Applicant(s):</b> Yamakawa, et al.			
<b>INFORMATION DISCLOSURE STATEMENT</b> <b>BY APPLICANT</b>		<b>Filing Date:</b> December 29, 2003	<b>Group Art Unit:</b> 2857

### U.S. PATENT DOCUMENTS

EXAM. INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
/K.W./	A	6,514,767	2/4/03	Michael Natan	436	166	

### FOREIGN PATENT DOCUMENTS

EXAM. INITIALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION (YES/NO)

### OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages)

/K.W./	B	Doering, et al., "Spectroscopic Tags Using Dye-Embedded Nanoparticles and Surface -Enhanced Raman Scattering", <i>Analytical Chemistry</i> , :5-9
/K.W./	C	Fuh, et al., "Analytical SPLITT Fractionation: Rapid Particle Size Analysis and Measurement of Oversized Particles", <i>Anal Chem. Soc.</i> 64:3125-3132 (1992)
/K.W./	D	Gale, et al., "A Micromachined Electrical Field-Flow Fractionation ( $\mu$ -EFF) System", <i>IEEE</i> 45(12):1459-1469, (1998).
/K.W./	E	Mulvaney, et al., "Glass-Coated, Analyte-Tagged Nanoparticles: A New Tagging System Based on Detection with Surface-Enhanced Raman Scattering", <i>Am Chem Soc.</i> 19:4784-4790 (2003).

<b>EXAMINER</b> GT6421411.1 1090132-5	<b>DATE CONSIDERED</b> /P. Kathryn Wright/ (05/03/2007)
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**EXAMINER:** Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.